

Application/Control No.	Applicant(s)/Patent under Reexamination	
10/724,325	CRUZ ET AL.	
Examiner	Art Unit	
Paul D. Kim	3729	

	SEARCHED				
Class	Subclass	Date	Examiner		
29	592.1 825 827 831 832 846	4/11/2006	PK		
174	52.4				
257	678 684	/			
438	118	₩ .			

INTERFERENCE SEARCHED				
Class	Subclass	Date	Examiner	
	ext Search achment	6/28/2006	PK	

	CH NOTES EARCH STRATEGY	·)
	DATE	EXMR
Consulted Sara Crane (257) No Search	4/11/2006	PK
Scott Geyer (438)	4/11/2006	PK
Carl Arbes (29)	4/12/2006	PK
Text Search EAST/NPL (IEEE)	4/12/2006	PK
Updated Text Search EAST/PGPub	6/28/2006	PK